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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10084563	FILING DATE 02/26/2002	CLASS 438	SUBCLASS 682	GAU 2812	EXAMINER ...
<p>**APPLICANTS: Lopatin Sergey; Nickel Alexander; King Paul;</p>					
<p>**CONTINUING DATA VERIFIED: <i>Lee</i> NONE</p>					
<p>** FOREIGN APPLICATIONS VERIFIED: <i>Lee</i> NONE</p>					
PG-PUB DO NOT PUBLISH <input checked="" type="checkbox"/>		RESCIND <input type="checkbox"/>			
Foreign priority claimed 35 USC 119 conditions met Verified and Acknowledged Examiner's initials		<input type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO P1410	
TITLE : Method of reducing electromigration by forming an electroplated copper-zinc interconnect and a semiconductor device thereby formed					

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Assistant Examiner	Total Claims Print Claim for O.G.
ISSUE FEE		Primary Examiner	DRAWING
Amount Due	Date Paid		Sheets Drawg. Figs. Drawg. Print F.
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	Application Examiner
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